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Fairchild Semiconductor NZT749

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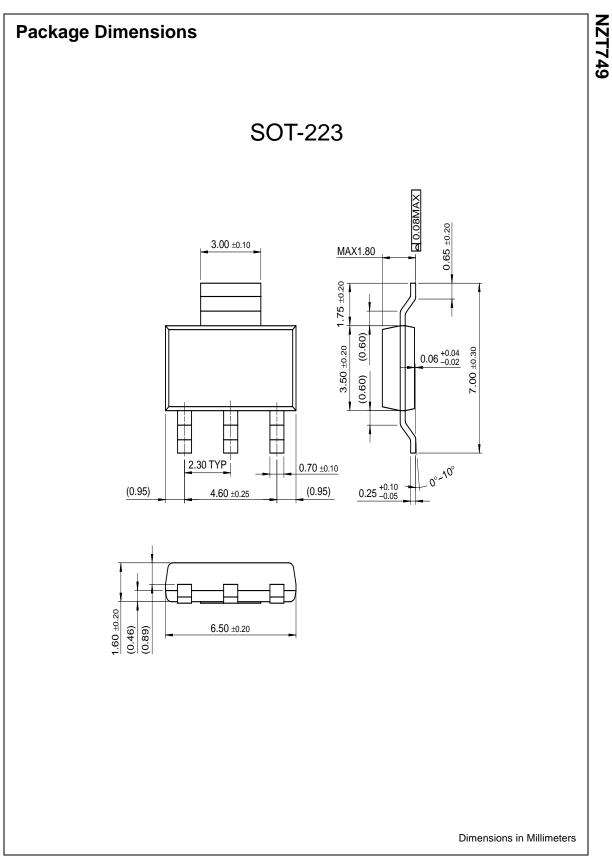


	CHILD				
EMICO	NDUCTOR®	77740			
	NZ	ZT749			
NP Cur	rrent Driver Transistor				
This device circuit whe	e is designed for power amplifier, regulator a re speed is important.	nd switching	4		
Sourced fro	om process 5P.			2	3
				1 SOT-2	223
			1. Base 2, 4. C		
bealute	e Maximum Ratings* T _{a=25°} C u	alaan atha muine anata d	1. 0030 2, 4. 0		
			Value		Unite
Symbol	Collector-Emitter Voltage		Value -25		Units V
/ _{СЕО} / _{СВО}	Collector-Base Voltage		-25		V
СВО			-5.0		V
1		Emitter-Base Voltage Collector Current (DC) - Continuous			
		NIQUS			
С	-		-5.0 -4.0 - 55 ~ 150		A °C
DTES:	Collector Current (DC) - Contin Operating and Storage Junction Temp re limiting values above which the serviceability of any semi	iconductor device may be impaired.	-4.0		A
C ГJ, T _{STG} hese ratings ar DTES: These ratings a These are stea	Collector Current (DC) - Contin Operating and Storage Junction Temp	ees C. tions involving pulsed or low duty cycle of	-4.0 - 55 ~ 150		A
C ГJ, T _{STG} hese ratings ar DTES: These ratings a These are stea	Collector Current (DC) - Contin Operating and Storage Junction Temp re limiting values above which the serviceability of any semi are based on a maximum junction temperature of 150 degr ady state limits. The factory should be consulted on applicat	ees C. tions involving pulsed or low duty cycle of	-4.0 - 55 ~ 150	Max.	A
C TJ, T _{STG} hese ratings ar DTES: These ratings These are stea Clectrica Symbol	Collector Current (DC) - Contin Operating and Storage Junction Temp re limiting values above which the serviceability of any semi are based on a maximum junction temperature of 150 degr ady state limits. The factory should be consulted on applicat al Characteristics T _a =25°C unless Parameter	operature Range conductor device may be impaired. ees C. tions involving pulsed or low duty cycle of otherwise noted	-4.0 - 55 ~ 150	Max.	A °C
C TJ, T _{STG} hese ratings ar DTES: These ratings these these are stear Clectrica Symbol Dff Charact	Collector Current (DC) - Contin Operating and Storage Junction Temp re limiting values above which the serviceability of any semi are based on a maximum junction temperature of 150 degr ady state limits. The factory should be consulted on applicat al Characteristics T _a =25°C unless Parameter	operature Range iconductor device may be impaired. ees C. tions involving pulsed or low duty cycle of otherwise noted Test Condition I _C = -10mA, I _B = 0	-4.0 - 55 ~ 150	Max.	A °C
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C TJ, T _{STG} hese ratings ar DTES: These ratings in These are stean Iectrica Symbol Dff Charact /(BR)CEO /(BR)CBO	Collector Current (DC) - Contin Operating and Storage Junction Temp re limiting values above which the serviceability of any semi are based on a maximum junction temperature of 150 degr ady state limits. The factory should be consulted on applical Al Characteristics T _a =25°C unless Parameter teristics Collector-Emitter Voltage	Image Image conductor device may be impaired. ees C. tions involving pulsed or low duty cycle of otherwise noted Ic = -10mA, I _B = 0 I _C = -10µA, I _E = 0 I _E = -10µA, I _C = 0	-4.0 - 55 ~ 150 operations Min. -25	Max.	A °C Units
C TJ, T _{STG} hese ratings ar DTES: These ratings ar These ratings ar these are stea Iectrica Symbol Dff Charact /(BR)CEO /(BR)CBO /(BR)EBO	Collector Current (DC) - Contin Operating and Storage Junction Temp re limiting values above which the serviceability of any semi are based on a maximum junction temperature of 150 degr ady state limits. The factory should be consulted on applicat al Characteristics Parameter teristics Collector-Emitter Voltage Collector-Base Voltage	Image Image conductor device may be impaired. ees C. tions involving pulsed or low duty cycle of otherwise noted Ic = -10mA, I _B = 0 I _C = -10µA, I _E = 0 I _E = -10µA, I _C = 0 V _{CB} = -30V, I _E = 0	-4.0 - 55 ~ 150 operations Min. -25 -35	Max.	A °C Units V V
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C TJ, T _{STG} hese ratings ar DTES: These ratings ar Dese ratings ar lectrica Symbol Dff Charact /(BR)CEO /(BR)CBO /(BR)EBO CBO EBO Dn Charact	Collector Current (DC) - Contin Operating and Storage Junction Temp re limiting values above which the serviceability of any semi are based on a maximum junction temperature of 150 degrady state limits. The factory should be consulted on applicat al Characteristics Parameter teristics Collector-Emitter Voltage Collector-Base Voltage Emitter-Base Voltage Collector Cut-off Current Emitter Cut-off Current teristics *	Derature Range conductor device may be impaired. ees C. tions involving pulsed or low duty cycle of otherwise noted Ic = -10mA, I _B = 0 Ic = -10µA, I _E = 0 Ic = -10µA, I _C = 0 V _{CB} = -30V, I _E = 0 V _{EB} = -4V, I _C = 0 V _{CE} = -2.0V, I _C = -50mA V _{CE} = -2.0V, I _C = -1.0A	-4.0 - 55 ~ 150 opperations Min. -25 -35 -5.0 -5.0 70 80	-100	A °C Units V V V V V
C TJ, T _{STG} hese ratings ar DTES: These ratings ar These ratings ar CBC CBC These ratings ar CBC CBC CBC CBC CBC CBC CBC CB	Collector Current (DC) - Contin Operating and Storage Junction Temp re limiting values above which the serviceability of any semi are based on a maximum junction temperature of 150 degrady state limits. The factory should be consulted on applicate al Characteristics Parameter teristics Collector-Emitter Voltage Collector-Base Voltage Emitter-Base Voltage Collector Cut-off Current teristics * DC Current Gain	Derature Range conductor device may be impaired. ees C. tions involving pulsed or low duty cycle of otherwise noted Ic = -10mA, I _B = 0 Ic = -10µA, I _E = 0 I _E = -10µA, I _C = 0 V _{CB} = -30V, I _E = 0 V _{EB} = -4V, I _C = 0 V _{CE} = -2.0V, I _C = -50mA V _{CE} = -2.0V, I _C = -2.0A	-4.0 - 55 ~ 150 opperations Min. -25 -35 -5.0 -5.0 70	-100 -0.1 300	A °C Units V V V V N μA
C C J, T _{STG} hese ratings ar DTES: These ratings ar These ratings ar CBC Symbol Dff Charact /(BR)CBO /(BR)CBO /(BR)EBO CBO EBO Dn Charact DFF CE(sat)	Collector Current (DC) - Contin Operating and Storage Junction Temp re limiting values above which the serviceability of any semi are based on a maximum junction temperature of 150 degr ady state limits. The factory should be consulted on applical Al Characteristics Parameter teristics Collector-Emitter Voltage Collector Base Voltage Emitter-Base Voltage Collector Cut-off Current Emitter Cut-off Current teristics * DC Current Gain Collector-Emitter Saturation Voltage	berature Range conductor device may be impaired. ees C. tions involving pulsed or low duty cycle of otherwise noted Ic = -10mA, I _B = 0 I _C = -10µA, I _E = 0 I _E = -10µA, I _E = 0 V _{CB} = -30V, I _E = 0 V _{EB} = -4V, I _C = 0 V _{CE} = -2.0V, I _C = -50mA V _{CE} = -2.0V, I _C = -1.0A V _{CE} = -2.0V, I _C = -1.0A V _{CE} = -1.0A, I _B = -100mA	-4.0 - 55 ~ 150 opperations Min. -25 -35 -5.0 -5.0 70 80	-100 -0.1 300 -0.3	A °C Units V V V V V
C C J, T _{STG} hese ratings ar DTES: These ratings ar These ratings ar lectrica Symbol Dff Charact /(BR)CBO /(BR)CBO /(BR)EBO CBO EBO Dn Charact PFE / /CE(sat) /BE(sat)	Collector Current (DC) - Contin Operating and Storage Junction Temp re limiting values above which the serviceability of any semi are based on a maximum junction temperature of 150 degr ady state limits. The factory should be consulted on applical Al Characteristics Parameter teristics Collector-Emitter Voltage Collector Base Voltage Emitter-Base Voltage Collector Cut-off Current teristics * DC Current Gain Collector-Emitter Saturation Voltage	Image Image conductor device may be impaired. ees C. tions involving pulsed or low duty cycle of therwise noted Test Condition Ic = -10mA, I _B = 0 I _C = -10µA, I _E = 0 I _E = -10µA, I _E = 0 I _E = -10µA, I _E = 0 V _{CB} = -30V, I _E = 0 V _{CB} = -30V, I _E = 0 V _{CE} = -2.0V, I _C = -50mA V _{CE} = -2.0V, I _C = -50mA V _{CE} = -2.0V, I _C = -1.0A I _C = -1.0A, I _B = -100mA I _C = -1.0A, I _B = -100mA I _C = -1.0A, I _B = -100mA	-4.0 - 55 ~ 150 opperations Min. -25 -35 -5.0 -5.0 70 80	-100 -0.1 300 -0.3 -1.25	A °C Units V V V V V V V V V V V V V V V V V V V
C C J, T _{STG} hese ratings ar DTES: These ratings ar These ratings ar lectrica Symbol Dff Charact /(BR)CEO /(BR)CEO /(BR)CEO /(BR)EBO CBO EBO Dn Charact DFE /CE(sat) /BE(sat) /BE(on)	Collector Current (DC) - Contin Operating and Storage Junction Temp re limiting values above which the serviceability of any semi are based on a maximum junction temperature of 150 degr ady state limits. The factory should be consulted on applical Al Characteristics Parameter teristics Collector-Emitter Voltage Collector Base Voltage Emitter-Base Voltage Collector Cut-off Current Emitter Cut-off Current teristics * DC Current Gain Collector-Emitter Saturation Voltage	berature Range conductor device may be impaired. ees C. tions involving pulsed or low duty cycle of otherwise noted Ic = -10mA, I _B = 0 I _C = -10µA, I _E = 0 I _E = -10µA, I _E = 0 V _{CB} = -30V, I _E = 0 V _{EB} = -4V, I _C = 0 V _{CE} = -2.0V, I _C = -50mA V _{CE} = -2.0V, I _C = -1.0A V _{CE} = -2.0V, I _C = -1.0A V _{CE} = -1.0A, I _B = -100mA	-4.0 - 55 ~ 150 opperations Min. -25 -35 -5.0 -5.0 70 80	-100 -0.1 300 -0.3	A °C Units V

Symbol	Parameter	Max.	Units
PD	Total Device Dissipation	1.2	W
	Derate above 25°C	9.7	mW/°C
R _{0JA}	Thermal Resistance, Junction to Ambient	103	°C/W

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•	haustive list of all such trad		conductor owns or is author	
	FAST [®]		David C 17TM	
ACEx™		ISOPLANAR™	Power247™	SuperFET™
ActiveArray™	FASTr™	LittleFET™	PowerSaver™	SuperSOT™-3
Bottomless™	FPS™	MICROCOUPLER™	PowerTrench [®]	SuperSOT™-6
CoolFET™	FRFET™	MicroFET™	QFET [®]	SuperSOT™-8
CROSSVOLT™	GlobalOptoisolator™	MicroPak™	QS™	SyncFET™
DOME™	GTO™	MICROWIRE™	QT Optoelectronics™	TinyLogic [®]
EcoSPARK™	HiSeC™	MSX™	Quiet Series [™]	TINYOPTO™
E ² CMOS™	I ² C™	MSXPro™	RapidConfigure™	TruTranslation [⊤]
EnSigna™	<i>i-Lo</i> ™	OCX™	RapidConnect™	UHC™
FACT™	ImpliedDisconnect™	OCXPro™	µSerDes™	UltraFET [®]
FACT Quiet Series	тм	OPTOLOGIC [®]	SILENT SWITCHER [®]	VCX™
Across the board. Around the world.™		OPTOPLANAR™	SMART START™	
The Power Franchise [®]		PACMAN™	SPM™	
Programmable Active Droop [™]		POP™	Stealth™	

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2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

PRODUCT STATUS DEFINITIONS

Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
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